

**DESCRIPTION**

The AM1013AD is available in SOP8 Package.

BVDSS	RDS(ON)	ID
100V	95mΩ	3.5A

APPLICATION

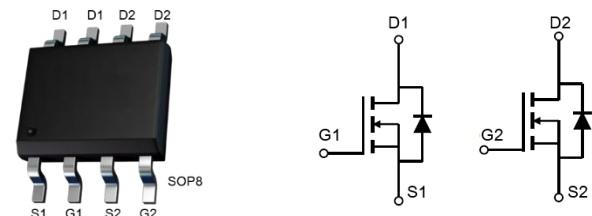
- DC/DC Converter
- LED Backlighting
- Motor Control

ORDERING INFORMATION

Package Type	Part Number	
SOP8 SPQ: 4,000pcs/Reel	M8	AM1013ADM8VR
Note	V: Halogen free Package R: Tape & Reel	
AiT provides all RoHS products		

FEATURES

- 100V, 3.5A
 $R_{DS(ON)}$ Typ = 95mΩ @ $V_{GS} = 10V$
 $R_{DS(ON)}$ Typ = 135mΩ @ $V_{GS} = 4.5V$
- Advanced Trench MOS with Split-Gate Structure
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- Lead Free

PIN DESCRIPTION

Pin#	Symbol	Function
1,3	S	Source
2,4	G	Gate
5,6,7,8	D	Drain

ABSOLUTE MAXIMUM RATINGS

$T_J = 25^\circ\text{C}$, unless otherwise specified.

V _{DS} , Drain-to-Source Voltage		100V
V _{GS} , Gate-to-Source Voltage		±20V
I _D , Continuous Drain Current	T _A = 25°C	3.5A
	T _A = 100°C	2.2A
I _{DM} , Pulsed Drain Current ⁽¹⁾		14A
E _{AS} , Single Pulsed Avalanche Energy ⁽²⁾		7.2mJ
P _D , Power Dissipation	T _A = 25°C	3.1W
R _{θJA} , Thermal Resistance, Junction to Ambient ⁽³⁾		40.3°C/W
T _J , T _{STG} , Junction & Storage Temperature Range		-55°C ~ +150°C

Stresses above may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated in the Electrical Characteristics are not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

(1) Repetitive rating, pulse width limited by junction temperature $T_J(\text{MAX}) = 150^\circ\text{C}$.

(2) The EAS data shows Max. rating. The test condition is $T_J = 25^\circ\text{C}$, $V_{DD} = 25V$, $V_G = 10V$, $R_G = 25\Omega$, $L = 0.4mH$, $I_{AS} = 6A$

(3) $R_{\theta JA}$ is measured with the device mounted on 1inch² pad of 2oz copper FR4 PCB.

**ELECTRICAL CHARACTERISTICS**T_J=25°C, unless otherwise specified.

Parameter	Symbo l	Conditions	Min	Typ.	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =250μA	100	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} = 0V	-	-	±100	nA
On Characteristics						
Gate Threshold Voltage	V _{GS (th)}	V _{DS} =V _{GS} , I _D =250μA	1	1.65	2.5	V
Static Drain Source ON-Resistance ⁽⁴⁾	R _{DS(ON)}	V _{GS} =10V, I _D =3A	-	95	130	mΩ
		V _{GS} =4.5V, I _D =1A	-	135	190	mΩ
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =50V, V _{GS} =0V, f=1MHz	-	200	-	pF
Output Capacitance	C _{OSS}		-	300	-	
Reverse Transfer Capacitance	C _{rss}		-	3	-	
Total Gate Charge	Q _g	V _{GS} =0 to 10V, V _{DS} =50V, I _D =3A	-	4	-	nC
Gate Source Charge	Q _{gs}		-	0.9	-	
Gate-Drain (“Miller”) Charge	Q _{gd}		-	1.1	-	
Switching Characteristics						
Turn-On Delay Time	t _{d(on)}	V _{GS} =10V, V _{DD} =50V R _{GEN} =3Ω, I _D =3A	-	13	-	ns
Turn-On Rese Time	t _r		-	19	-	
Turn-Off Delay Time	t _{d(off)}		-	20	-	
Turn-Off Fall Time	t _f		-	28	-	
Drain-Source Diode Characteristics and Max Ratings						
Maximum Continuous Drain to Source Diode Forward Current	I _S	-	-	-	3.5	A
Maximum Pulsed Drain to Source Diode Forward Current	I _{SM}	-	-	-	14	A
Drain to Source Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _S =3A	-	-	1.2	V

(4) Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%.



TYPICAL PERFORMANCE CHARACTERISTICS

Fig 1. Output Characteristics

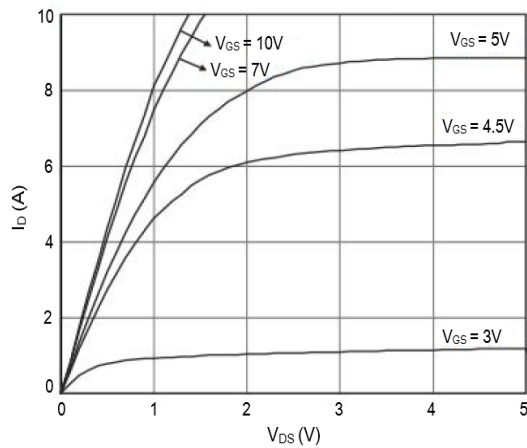


Fig 2. Typical Transfer Characteristics

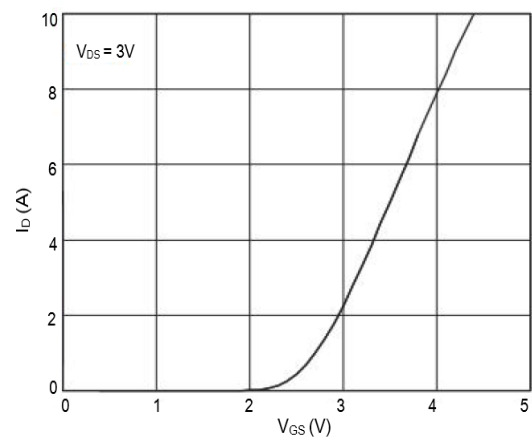


Fig 3. On-resistance vs. Drain Current

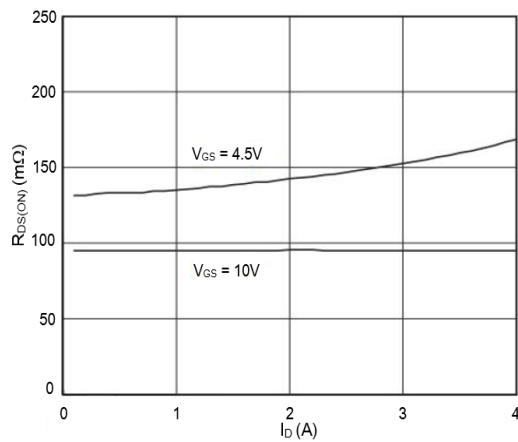


Fig 4. Body Diode Characteristics

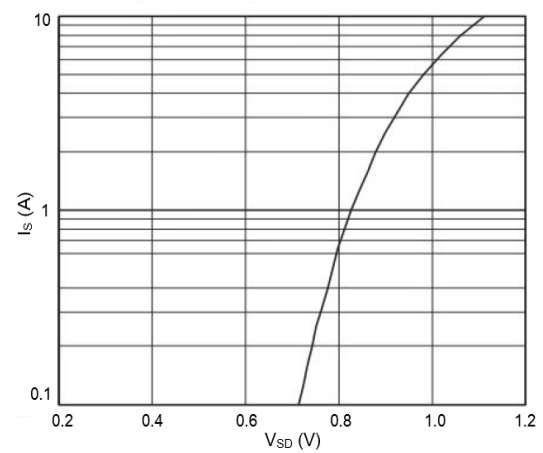


Fig 5. Gate Charge Characteristics

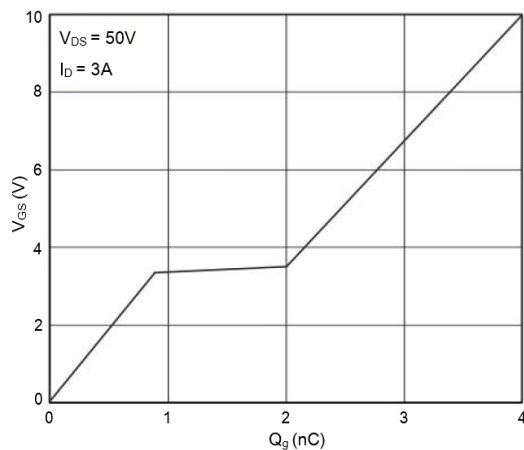


Fig 6. Capacitance Characteristics

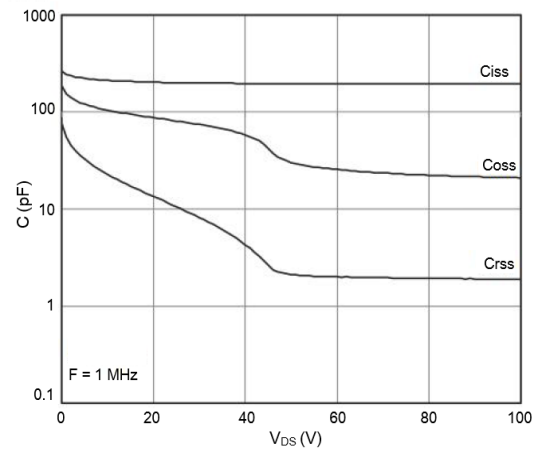




Fig 7. Normalized Breakdown voltage vs. Junction Temperature

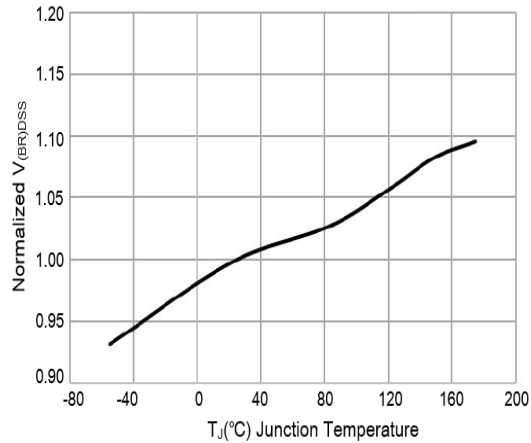


Fig 8. Normalized on Resistance vs. Junction Temperature

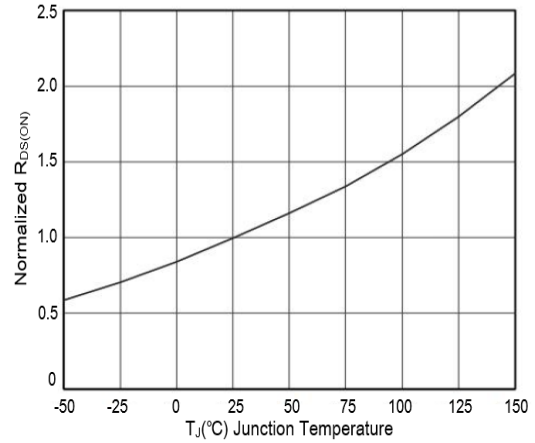


Fig 9. Maximum Safe Operating Area

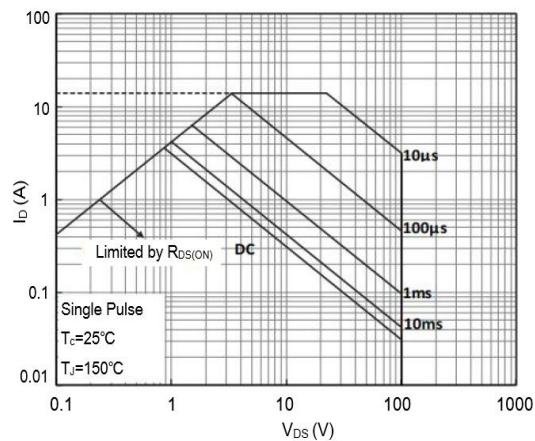


Fig 10. Maximum Continuous Drain Current vs. Case Temperature

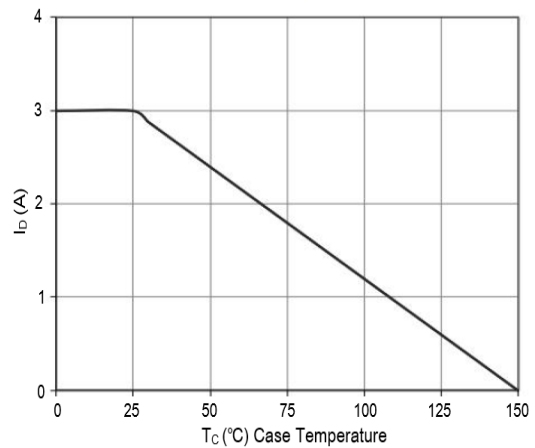


Fig 11. Normalized Maximum Transient Thermal Impedance

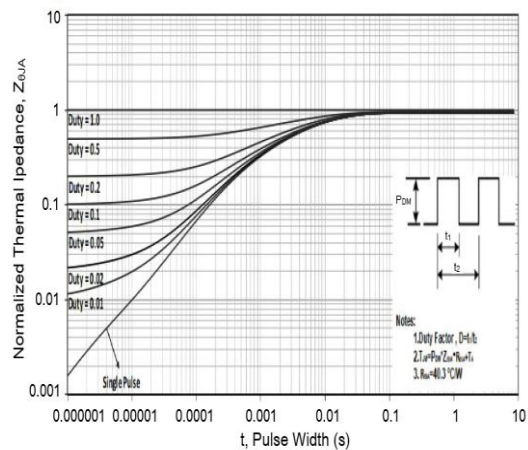
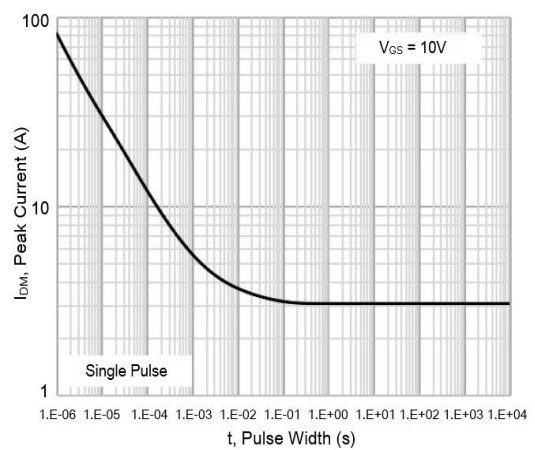


Fig 12. Peak Current Capacity





TEST CIRCUIT

Fig 1. Gate Charge Test Circuit & Waveform

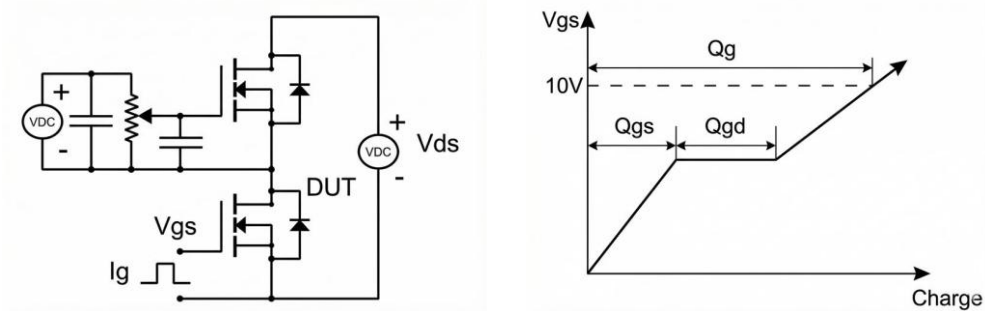


Fig 2. Resistive Switching Test Circuit & Waveform

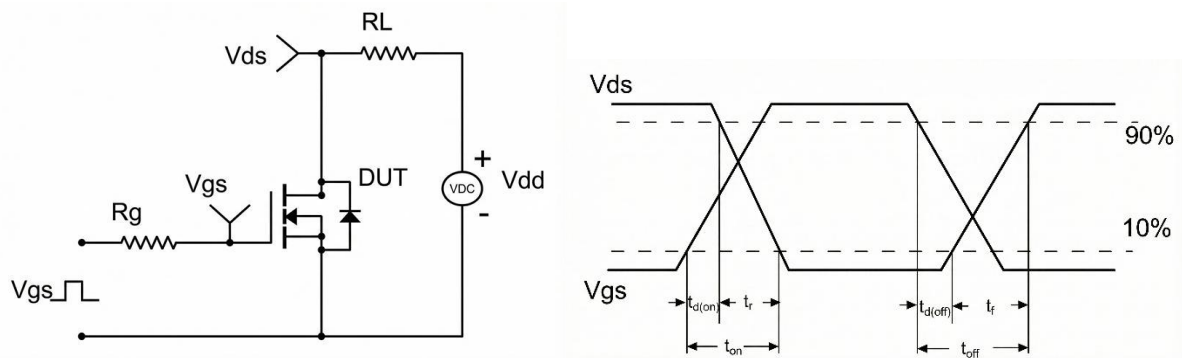


Fig 3. Unclamped Inductive Switching Test Circuit & Waveform

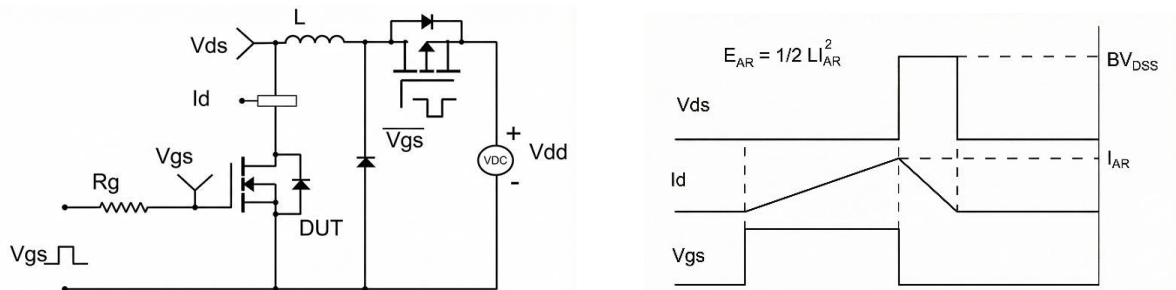
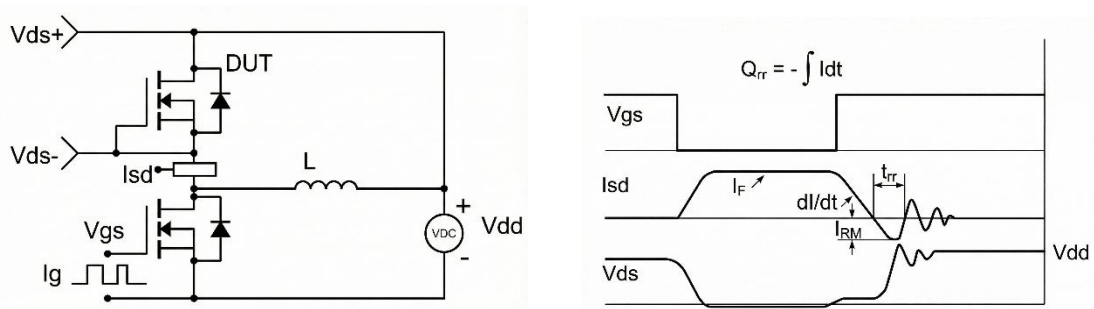


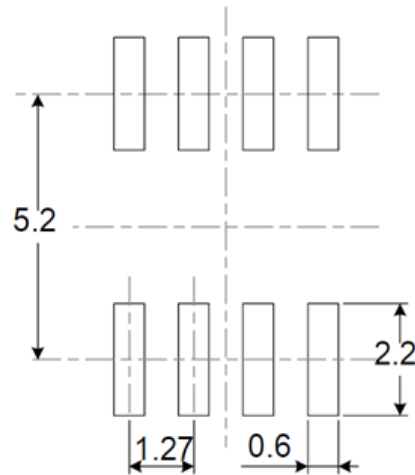
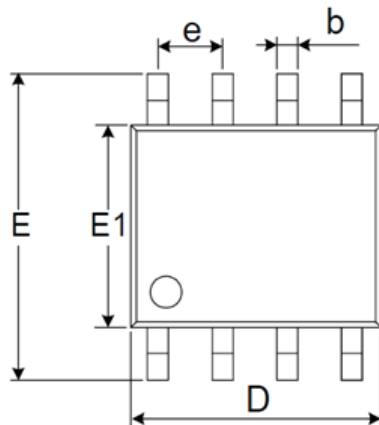
Fig 4. Diode Recovery Test Circuit & Waveform



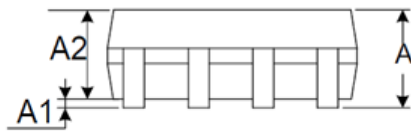


PACKAGE INFORMATION

Dimension in SOP8 (Unit: mm)



RECOMMENDED LAND PATTERN (Unit: mm)



Symbol	MILLIMETER	
	Min.	Max.
A	1.350	1.750
A1	0.100	0.250
A2	1.350	1.550
b	0.330	0.510
c	0.170	0.250
D	4.800	5.000
e	1.270 BSC	
E	5.800	6.200
E1	3.800	4.000
L	0.400	1.270
θ	0°	8°



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